



#134/72-03  
V. Jones

MS AF  
REPLY UNDER 37 C.F.R. § 1.116  
EXPEDITED PROCEDURE  
EXAMINING GROUP 2133

PATENT  
1248-0509P

IN THE U.S. PATENT AND TRADEMARK OFFICE

RECEIVED

Applicant: Kumi MIYACHI et al. Conf. No.: 3629 JUL 02 2003  
Appl. No.: 09/615,956 Group: 2133 Technology Center 2100  
Filed: July 13, 2000 Examiner: Abraham  
For: SEMICONDUCTOR DEVICE HAVING INTEGRALLY SEALED  
INTEGRATED CIRCUIT CHIPS ARRANGED FOR  
IMPROVED TESTING

REPLY

Assistant Commissioner of Patents  
and Trademarks

June 27, 2003

In response to the Office Action mailed June 11, 2003, the following amendments and remarks are respectfully submitted in connection with the above-identified application.

IN THE CLAIMS:

1. (Currently Amended) A semiconductor device, comprising:  
a plurality of chips, which are integrally sealed air-tight;  
a test signal input terminal for receiving an externally supplied test  
signal;

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